SCAS323 - JULY 1990 - REVISED MARCH 1994

Replaces SN74AS303 Maximum Output Skew Between Same Phase Outputs of 1 ns Maximum Pulse Skew of 1 ns	D OR N PACKAGE (TOP VIEW) Q3 1 16 Q2
TTL-Compatible Inputs and Outputs	Q4 [] 2 15 [] Q1 GND [] 3 14 [] CLR
Center-Pin V _{CC} and GND Configurations Minimize High-Speed Switching Noise Paskers Ontions Include Pleatie	GND 4
 Package Options Include Plastic Small-Outline Package (D) and Standard Plastic 300-mil DIPs (N) 	Q6 [7 10] PRE Q7 [8 9] Q8

description

The CDC303 contains eight flip-flops designed to have low skew between outputs. The eight outputs (six in-phase with CLK and two out-of-phase) toggle on successive CLK pulses. Preset (\overline{PRE}) and clear (\overline{CLR}) inputs are provided to set the Q and \overline{Q} outputs high or low independent of the clock (CLK) input.

The CDC303 has output and pulse-skew parameters $t_{sk(o)}$ and $t_{sk(p)}$ to ensure performance as a clock driver when a divide-by-two function is required.

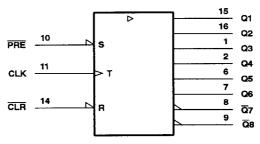
The CDC303 is characterized for operation from 0°C to 70°C.

FUNCTION TABLE

INPUTS			OUTPUTS		
CLR	PRE	CLK	Q1-Q6	<u>Q</u> 7− <u>Q</u> 8	
L	Н	X	L	Н	
н	L	×	н	L	
L	L	×	L†	L†	
Н	н	†	\overline{Q}_0	Q_0	
н	н	L	Qo	\overline{Q}_0	

† This configuration will not persist when PRE or CLR returns to its inactive (high) level.

logic symbol‡



[‡] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

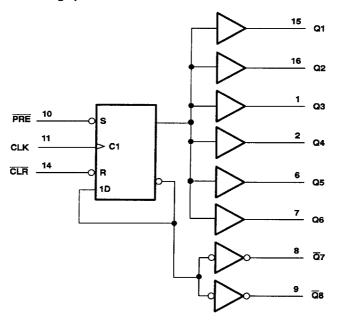
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logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}
input voltage, V _I
Operating free-air temperature range
Storage temperature range65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	V
VIH	High-level input voltage	2			V
VIL	Low-level input voltage			0.8	V
ЮН	High-level output current			-24	mA
loL	Low-level output current			48	mA
fclock	Input clock frequency			80	MHz
TA	Operating free-air temperature	0		70	°C



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT
VIK	V _{CC} = 4.5 V,	l _l = -18 mA			-1.2	٧
	V _{CC} = 4.5 V to 5.5 V,	l _{OH} = −2 mA	V _{CC} -2			٧
VOH	V _{CC} = 4.5 V,	I _{OH} = -24 mA	2	2.8		٧
VoL	V _{CC} = 4.5 V,	I _{OL} = 48 mA		0.3	0.5	>
l _l	V _{CC} = 5.5 V,	V _I = 7 V			0.1	mA
ήн	V _{CC} = 5.5 V,	V _I = 2.7 V			20	μΑ
կլ	V _{CC} = 5.5 V,	V _i = 0.4 V			-0.5	mA
lo‡	V _{CC} = 5.5 V,	V _O = 2.25 V	-50		-150	mA
Icc	V _{CC} = 5.5 V,	See Note 1		40	70	mA

[†] All typical values are at V_{CC} = 5 V, T_A = 25°C.

timing requirements

			MIN	MAX	UNIT
fclock	Clock frequency		0	80	MHz
	t _w Pulse duration	CLR or PRE low	5		
tw		CLK high	4		ns
	CLK low	6		i	
t _{su}	Setup time before CLK†	CLR or PRE inactive	6		ns

switching characteristics over recommended operating free-air temperature range (see Figure 1)

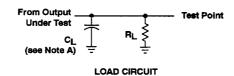
PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	MAX	UNIT
f _{max} §				80		MHz
t _{PLH}	CLK	Q, Q	R ₁ = 500 Ω, C ₁ = 50 pF	2	9	–l ns l
^t PHL	OLK	u, u	THE = 300 sz, OE = 30 pr	2	9	
t _{PLH}	PRE or CLR	Q, Q	R _L = 500 Ω, C _L = 50 pF	3	12	
^t PHL	PRE OF CLR	u , u	71, 2 3 3 3 4 5 2 3 5 pr	3	12	
		q			1	ns
t _{sk(o)}	CLK	ā	$R_L = 500 \Omega$, $C_L = 10 pF to 30 pF$, See Figure 2		1	
		Q, $\overline{\mathbf{Q}}$	- 000 Figuro 2		2	
^t sk(p)	CLK	a, a	$R_L = 500 \Omega$, $C_L = 10 pF to 30 pF$		1	ns
t _r					4.5	ns
tf					3.5	ns

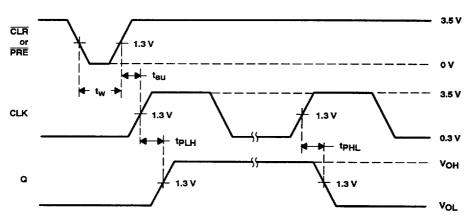
[§] f_{max} minimum values are at C_L = 0 to 30 pF.



[‡] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS. NOTE 1: ICC is measured with CLK and PRE grounded, then with CLK and CLR grounded.

PARAMETER MEASUREMENT INFORMATION





NOTES: A. C_L includes probe and jig capacitance.

B. Input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $t_f = 2.5$ ns, $t_f = 2.5$ ns.

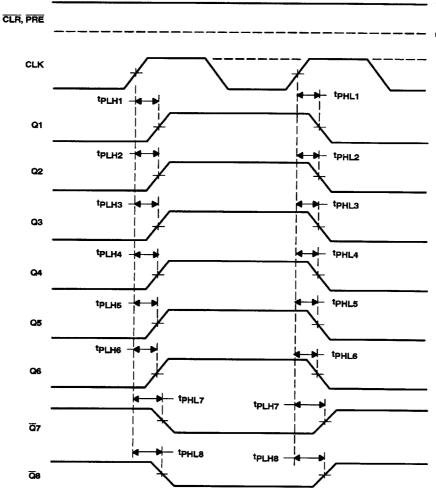
Figure 1. Load Circuit and Voltage Waveforms



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NOTES: A. t_{sk(o)}, CLK to Q, is calculated as the greater of:

- The difference between the fastest and slowest of tpLHn (n = 1, 2, 3, 4, 5, 6)
- The difference between the fastest and slowest of tpHLn (n = 1, 2, 3, 4, 5, 6)
- B. t_{sk(o)}, CLK to Q, is calculated as the greater of: | tpLH7 tpLH8 | and | tpHL7 tpHL8 |.
- C. tsk(o), CLK to Q and Q, is calculated as the greater of:
 - The difference between the fastest and slowest of tpLHn (n = 1, 2, 3, 4, 5, 6), tpHL7, and tpHL8
 - The difference between the fastest and slowest of tphln (n = 1, 2, 3, 4, 5, 6), tplh7, and tplh8
- D. $t_{sk(p)}$ is calculated as the greater of $|t_{PLHn} t_{PHLn}|$ (n = 1, 2, 3, ..., 8).

Figure 2. Waveforms for Calculation of tsk(o)

